

**AUTOMATED BIST TEST PATTERN SEQUENCE
GENERATOR SOFTWARE SYSTEM AND METHOD**

ABSTRACT OF THE DISCLOSURE

Methods and systems for reducing the volume of test data associated with built in self testing (BIST) test methodologies (e.g., logical BIST, array BIST, etc.) and pattern structures are provided. Rather than store the entire set of test parameters for each of a plurality of test sequences to be performed, as with conventional test systems, embodiments of the present invention only store a limited number of "dynamic" test parameters for each test sequence that have changed relative to a previous test sequence.